

**Образовательный и исследовательский центр информационных технологий**

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Профессор

## Publications

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*Статья*

### **Memory Physical Aware Multi-Level Fault Diagnosis Flow**

SAMVEL SHOUKOURIAN, GURGEN HARUTYUNYAN, SUREN MARTIROSYAN, YERVANT ZORIAN

IEEE Transactions on Emerging Topics in Computing 2020 700-711

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*Статья*

### **Fault Awareness for Memory BIST Architecture Shaped by Multidimensional Prediction Mechanism**

S. Shoukourian, G. Harutyunyan, Y. Zorian

IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems 2019 562-575

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*Статья*

### **Experimental study on Hamming and Hsiao Codes in the Context of Embedded Applications**

S. Shoukourian, G. Harutyunyan, G. Tshagharyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 25-28

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*Статья*

### **Automated Flow for Test Pattern Creation for IPs in SoC**

S. Shoukourian, G. Harutyunyan, D. Sargsyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 21-24

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*Статья*

### **An Efficient Testing Methodology for Embedded Flash Memories**

S. Shoukourian, G. Harutyunyan, S. Martirosyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 422-425

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*Статья*

### **Security Issues in Test and Repair Infrastructure for Systems-on-Chip**

S. Shoukourian, G. Harutyunyan, G. Tshagharyan

Информационно-коммуникационные технологии в науке, производстве и образовании ICIT-2017 2017 114-122

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*Конференция*

### **Extending fault periodicity table for testing faults in memories under 20nm.**

Gurgen Harutyunyan, Samvel K. Shoukourian, Valery A. Vardanian, Yervant Zorian

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*Конференция*

### **A power based memory BIST grouping methodology.**

Lusine Martirosyan, Gurgen Harutyunyan, Samvel K. Shoukourian, Yervant Zorian

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*Конференция*

**Overview study on fault modeling and test methodology development for FinFET-based memories.**

Grigor Tshagharyan, Gurgen Harutyunyan, Samvel K. Shoukourian, Yervant Zorian

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*Патент*

**Testing Electronic Memories Based on Fault and Test Algorithm Periodicity**

S. Shoukourian, G. Harutyunyan, V. Vardanian, A. Hakhumyan, Y. Zorian

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*Патент*

**FINFET-BASED MEMORY TESTING USING MULTIPLE READ OPERATIONS**

Samvel Shoukourian, Gurgen Harutyunyan, Grigor Tshagharyan, Yervant Zorian

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*Патент*

**DETECTION OF ADDRESS ERRORS IN MEMORY DEVICES USING MULTI-SEGMENT ERROR DETECTION CODES**

Samvel Shoukourian, Gurgen Harutyunyan, Hayk Grigoryan, Grigor Tshagharyan, Yervant Zorian

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